TOSHIBA Field Effect Transistor Silicon P-Channel MOS Type (U-MOS III)

TPCP8101

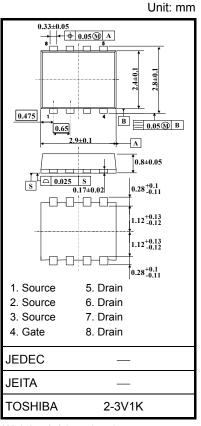
Notebook PC Applications Portable Equipment Applications

- Small footprint due to small and thin package
- Low drain-source ON-resistance: RDS (ON) = 24 m Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 14 \text{ S (typ.)}$
- Low leakage current: $IDSS = -10 \mu A \text{ (max) (V}_{DS} = -20 \text{ V)}$
- Enhancement model: $V_{th} = -0.5 \text{ to } -1.2 \text{ V}$

 $(V_{DS} = -10 \text{ V}, I_D = -200 \mu\text{A})$

Absolute Maximum Ratings (Ta = 25°C)

Characteristic			Symbol	Rating	Unit	
Drain-source voltage			V_{DSS}	-20	V	
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)			V_{DGR}	-20	V	
Gate-source voltage			V _{GSS}	± 8	V	
Drain current	DC	(Note 1)	ID	-5.6	Α	
Drain current	Pulse	(Note 1)	I _{DP}	-22.4	A	
Drain power dissipation	on	(t = 5 s) (Note 2a)	P_{D}	1.68	W	
Drain power dissipation	on	(t = 5 s) (Note 2b)	P_{D}	0.84	W	
Single-pulse avalanch	ne energ	y(Note 3)	E _{AS}	20.3	mJ	
Avalanche current			I _{AR}	-5.6	А	
Repetitive avalanche energy (Note 4)			E _{AR}	0.168	mJ	
Channel temperature			T _{ch}	150	°C	
Storage temperature	Storage temperature range			-55~150	°C	



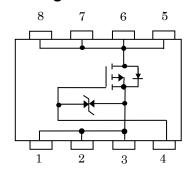
Weight: 0.017 g (typ.)

Note: For Notes 1 to 5, refer to the next page.

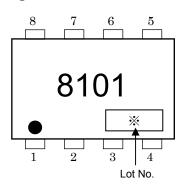
Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

This transistor is an electrostatic-sensitive device. Handle with care.

Circuit Configuration



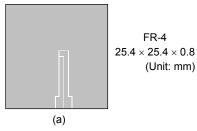
Marking (Note 5)

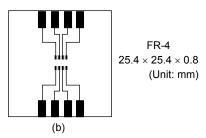


Thermal Characteristics

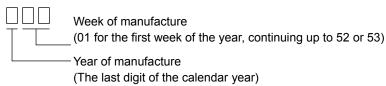
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	R _{th (ch-a)}	74.4	°C/W
Thermal resistance, channel to ambient (t = 5 s) (Note 2b)	R _{th (ch-a)}	148.8	°C/W

- Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.
- Note 2: (a) Device mounted on a glass-epoxy board (a)
- (b) Device mounted on a glass-epoxy board (b)





- Note 3: $V_{DD} =$ -16 V, $T_{ch} = 25^{\circ}C$ (initial), L = 0.5 mH, $R_{G} = 25~\Omega$, $I_{AR} =$ -5.6 A
- Note 4: Repetitive rating: pulse width limited by maximum channel temperature.
- Note 5: on the lower left of the marking indicates Pin 1.
 - * Weekly code (three digits):



2

TPCP8101



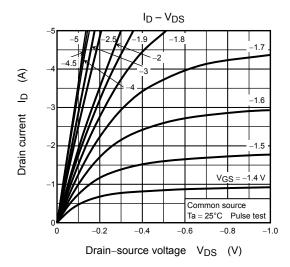
Electrical Characteristics (Ta = 25°C)

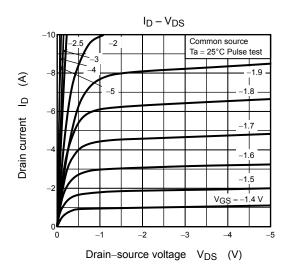
Ch	aracteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	rent	I _{GSS}	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cutoff curre	ent	I _{DSS}	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}$	_	_	-10	μА
Drain-source bre	akdown voltage	V _{(BR)DSS}	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	±10	\ \		
Brain-source bre	andown voltage	V _{(BR) DSX}	$I_D = -10 \text{ mA}, V_{GS} = 8 \text{ V}$	-12	- ±1010101.2 67 90 36 41 24 30 14 - 1550 - 215 - 265 - 7 - 13 - 21 -	v	
Gate threshold ve	oltage	V_{th}	$V_{DS} = -10 \text{ V}, I_D = -200 \mu\text{A}$	-0.5		-1.2	٧
			$V_{GS} = -1.8 \text{ V}, I_D = -1.4 \text{ A}$	<u> </u>		90	mΩ
Drain-source ON-resistance	R _{DS (ON)}	$V_{GS} = -2.5 \text{ V}, I_D = -2.8 \text{ A}$	_	36	41		
			$V_{GS} = -4.5 \text{ V}, I_D = -2.8 \text{ A}$	_	24	30	
Forward transfer	Forward transfer admittance		V _{DS} = -10 V, I _D = -2.8 A	7	14	_	S
Input capacitance		C _{iss}		_	1550	_	pF
Reverse transfer capacitance		C _{rss}	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	215	_	
Output capacitan	everse transfer capacitance utput capacitance			_	265	_	
	Rise time	t _r	V _{GS} 0 V] [I _D = -2.8 A	_	7	_	
0 11 11	Turn-on time	t _{on}	V _{GS} 0 V I _D = -2.8 A V _{OUT} V _{GS} V _{OUT} V _{GS} V _{OUT} V _{GS} V _{OUT} V _{GS} V _{GS}	10 -20120.51.2 -0.51.2 -0.67 90 - 36 41 - 24 30 - 14 1550 1550 265 7			
Switching time	Fall time	t _f	4.7.5. 3.4. 3.4. 0.0. 1.1.	_	21	_	ns
	Turn-off time	t _{off}	$V_{DD} \simeq -10 \text{ V}$ Duty $\leq 1\%$, $t_W = 10 \mu\text{s}$	_	68	_	
Total gate charge (gate-source plus gate-drain)		Qg	V _{DD} ≈ -16 V, V _{GS} = -5 V,	_	19	_	
Gate-source charge		Q _{gs}	$I_D = -5.6 \text{ A}$		14		nC
Gate-drain ("Mille	er") charge	Q_{gd}		_	5	_	

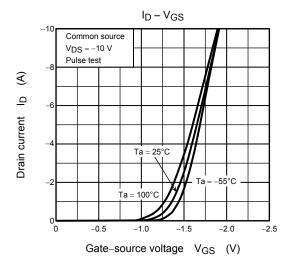
Source-Drain Ratings and Characteristics (Ta = 25°C)

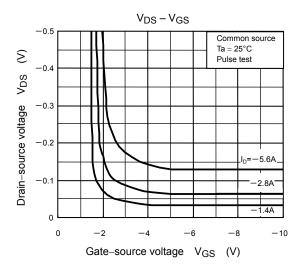
Charact	teristic	Symbol	Test Condition	Min Typ. Max		Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	_	ı	_	-22.4	А
Forward voltage ((diode)	V_{DSF}	$I_{DR} = -5.6 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	1.2	V

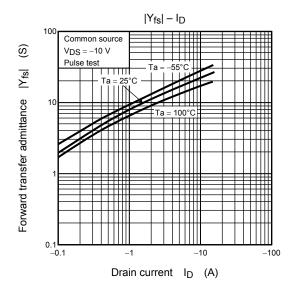
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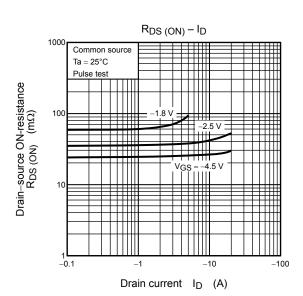


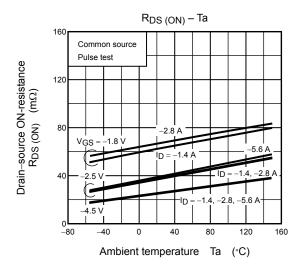


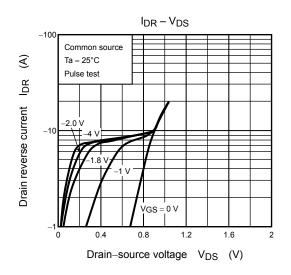


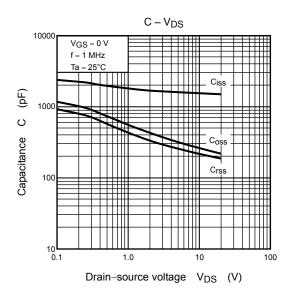


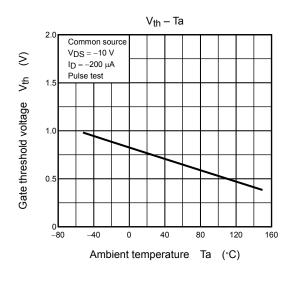


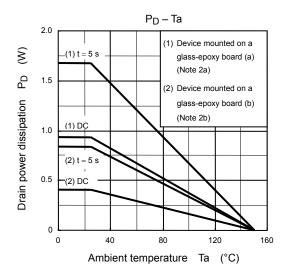


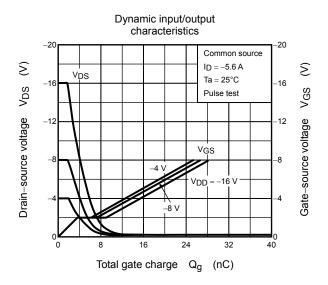




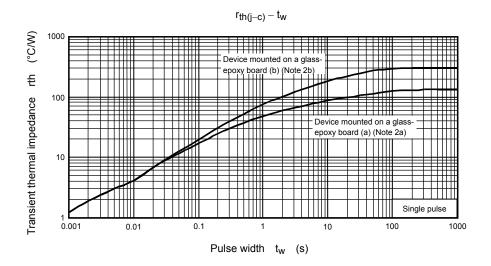


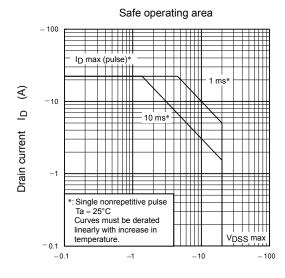






5





Drain-sour

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